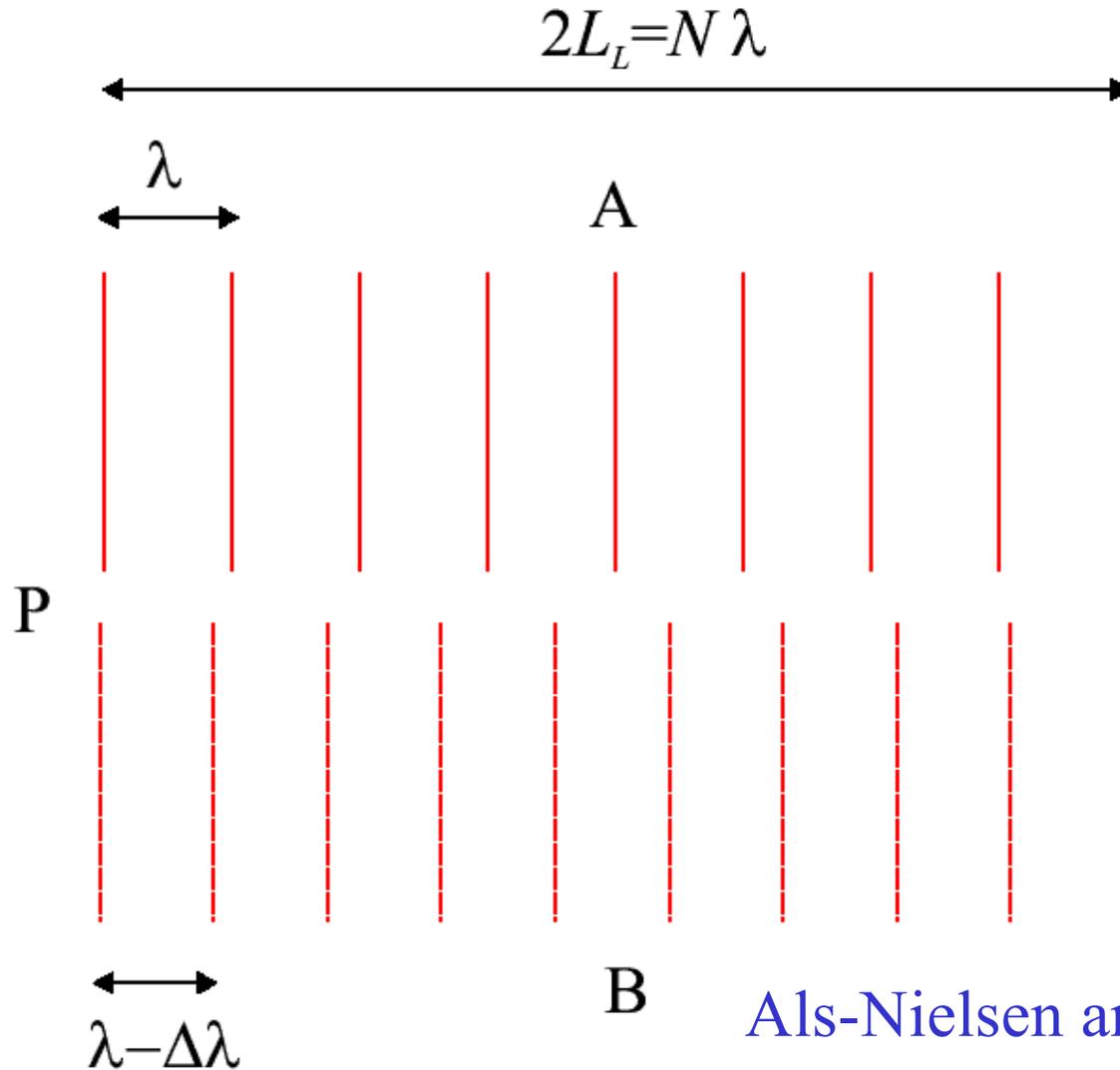


Coherent Scattering and Imaging

Ian Robinson
University of Illinois
8SXNS
29 June 2004

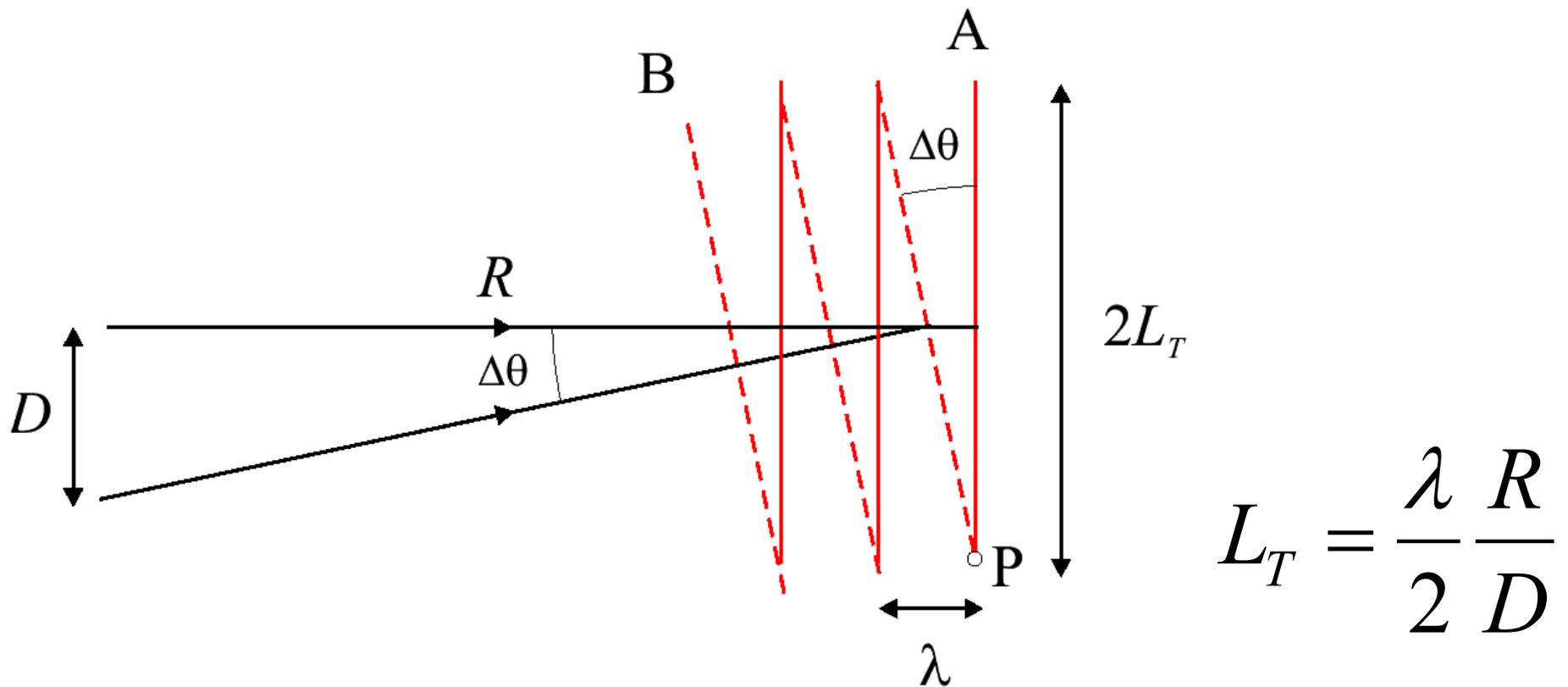
Longitudinal Coherence



$$L_L = \frac{1}{2} \frac{\lambda^2}{\Delta\lambda}$$

Als-Nielsen and McMorro (2001)

Lateral (Transverse) Coherence

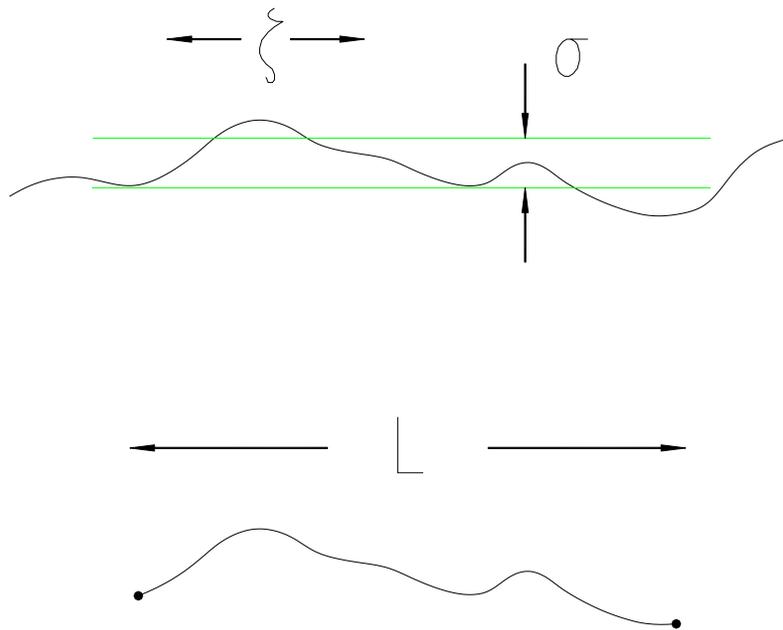


$$L_T = \frac{\lambda}{2} \frac{R}{D}$$

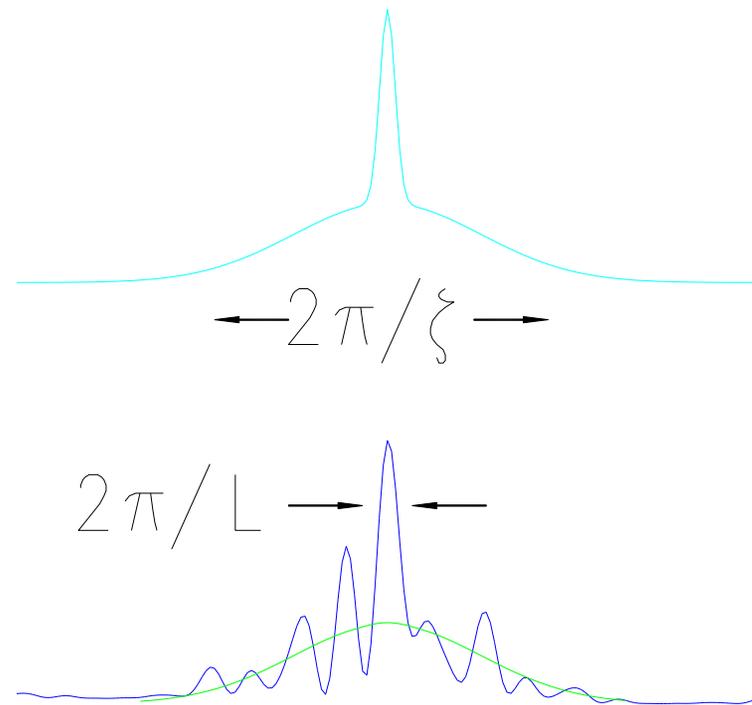
Als-Nielsen and McMorrow (2001)

Diffuse Scattering acquires Structure using CXD

Real Space



Reciprocal Space



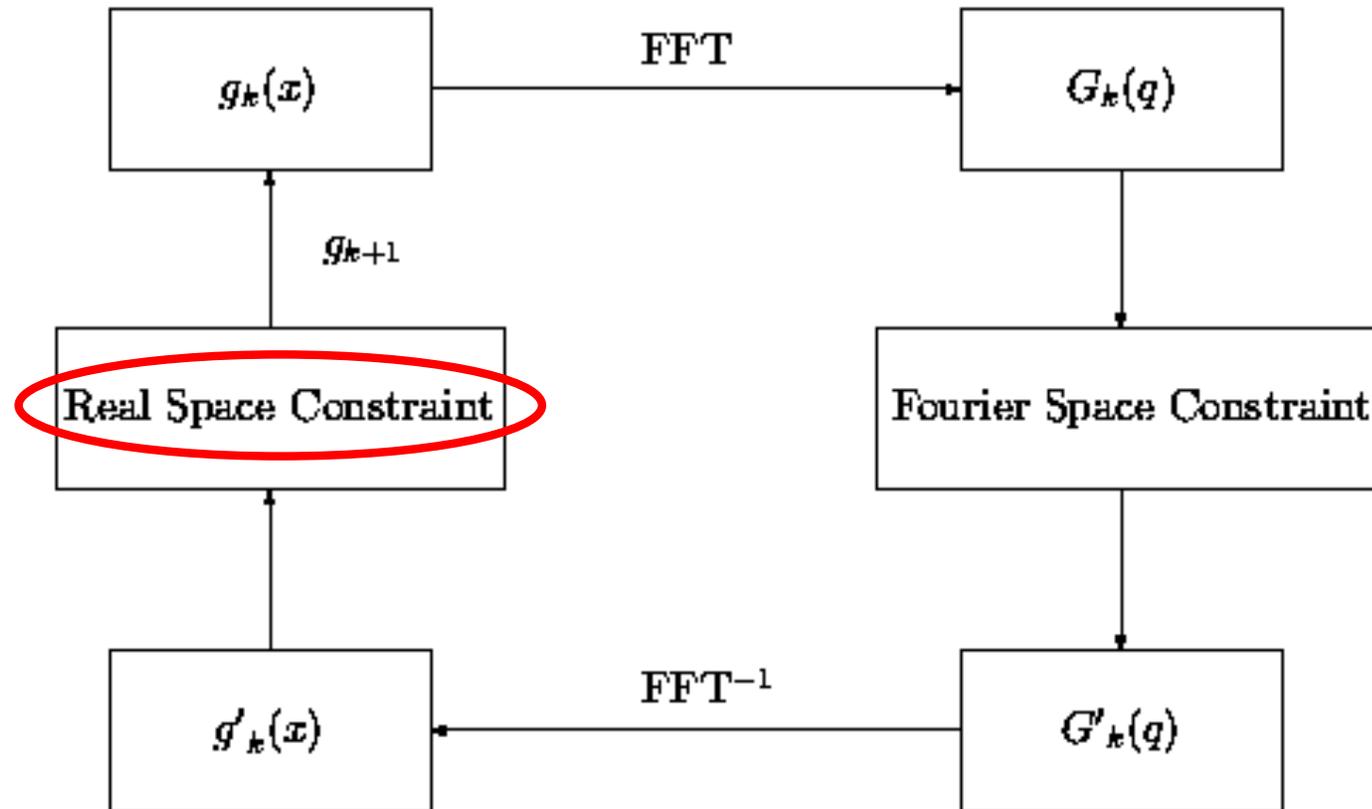
Rules of Life with Coherence

- No more diffuse scattering
- No more ensemble averaging
- Coherence is indestructible
 - everything following your (coherence-defining) entrance slit is your ‘sample’
- If something moves, the whole interference pattern changes

Applications of Coherence

- “Coherent X-ray Diffraction Microscope”
 - small objects (**Pfeiffer**)
 - magnetic domains (**Eisebitt**)
- X-ray Photon Correlation Spectroscopy
 - polymer melt dynamics (**Kim**)
 - liquid crystal films (**de Jeu**)
 - heterodyne fluctuations (**Madsen**)
- Phase objects ...

Iterative Phase Refinement



J. R. Fienup *Appl. Opt.* 21 2758 (1982)

R. W. Gerchberg and W. O. Saxton *Optik* 35 237 (1972)

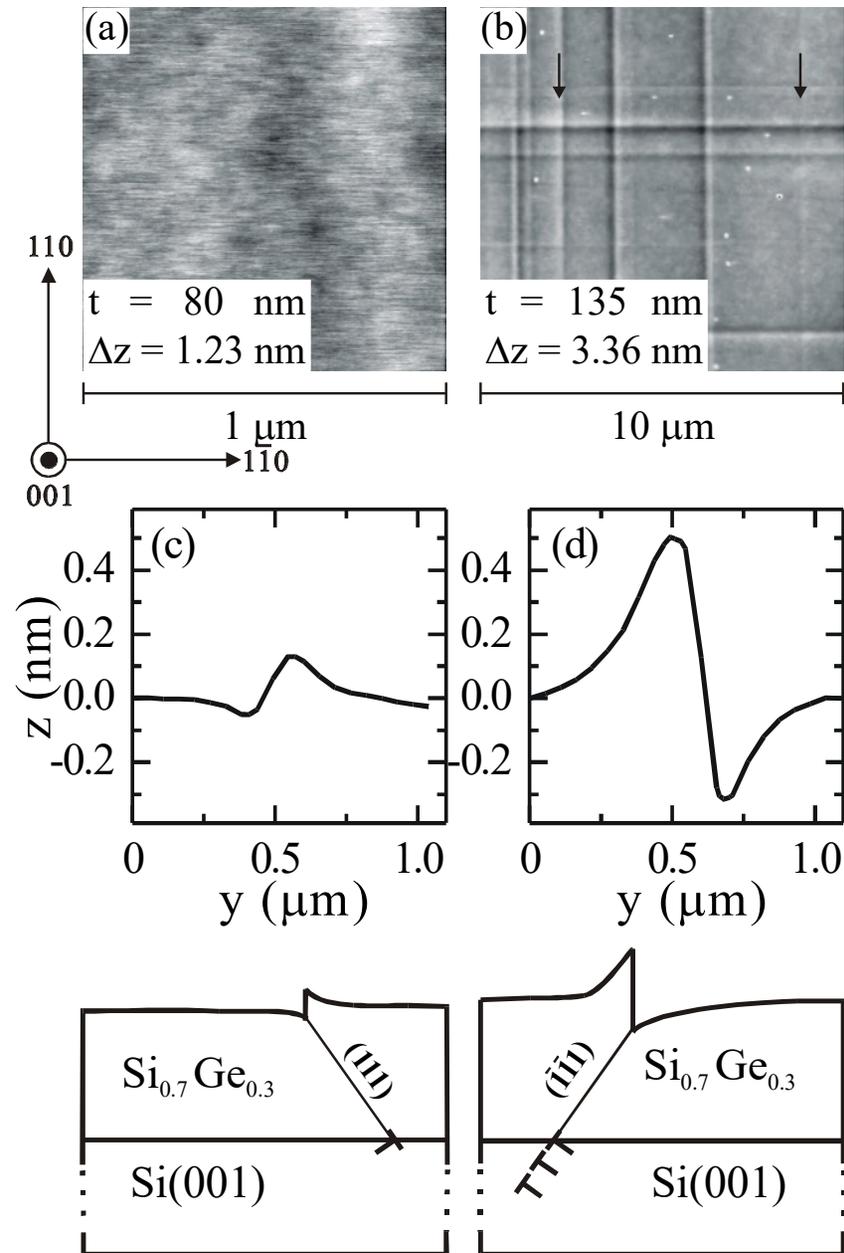
I. K. Robinson *Coherence*

Low dislocation density GeSi films

Thickness close to critical thickness

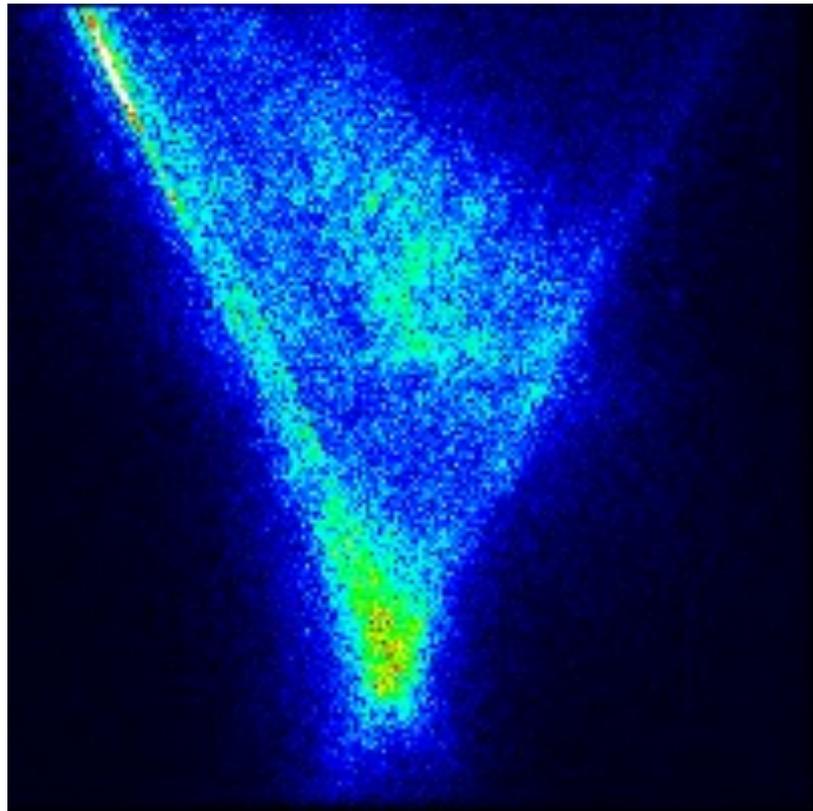
Dislocations aggregate at interface and glide to surface along $\{111\}$

T. Spila, UIUC Thesis

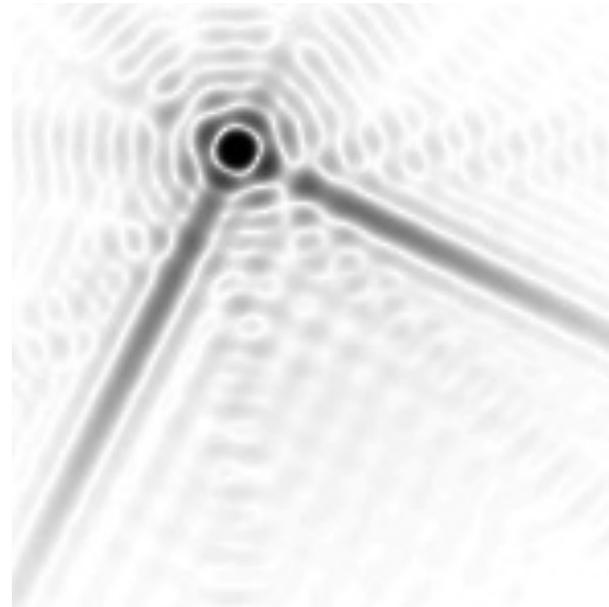
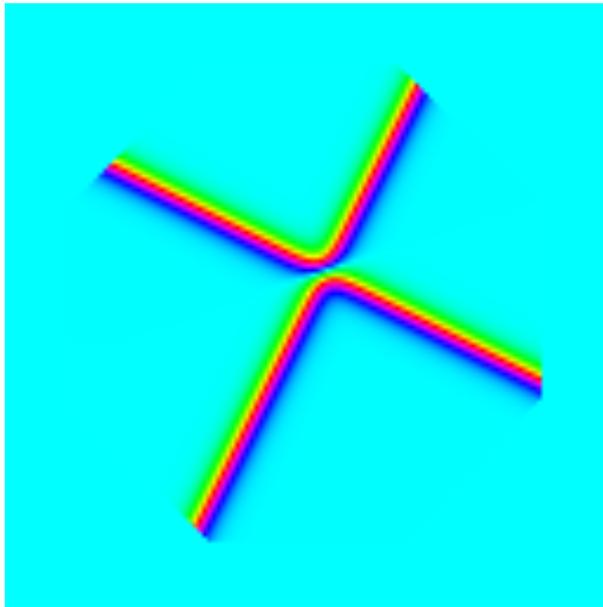


Use CCD and scan sample position

(2,0,1.92) 280nm thick $\text{Ge}_{0.3}\text{Si}_{0.7}$



Dislocation Diffraction



Multiple Dislocations

